United States Patent [19]

Chow

[11] **Patent Number: Des. 292,979**

[45] **Date of Patent: ** Dec. 1, 1987**

[54] **AUTOMATIC SEMICONDUCTOR WAFER TESTER**

[75] Inventor: **Marland Chow**, San Jose, Calif.

[73] Assignee: **Prometrix Corporation**, Santa Clara, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **727,417**

[22] Filed: **Apr. 26, 1985**

[52] **U.S. Cl.** **D10/75**; D10/46

[58] **Field of Search** .... D10/46, 75, 77, 78, D10/81, 102; 324/73 R, 73 AT, 73 PC, 158 F

[56] **References Cited**

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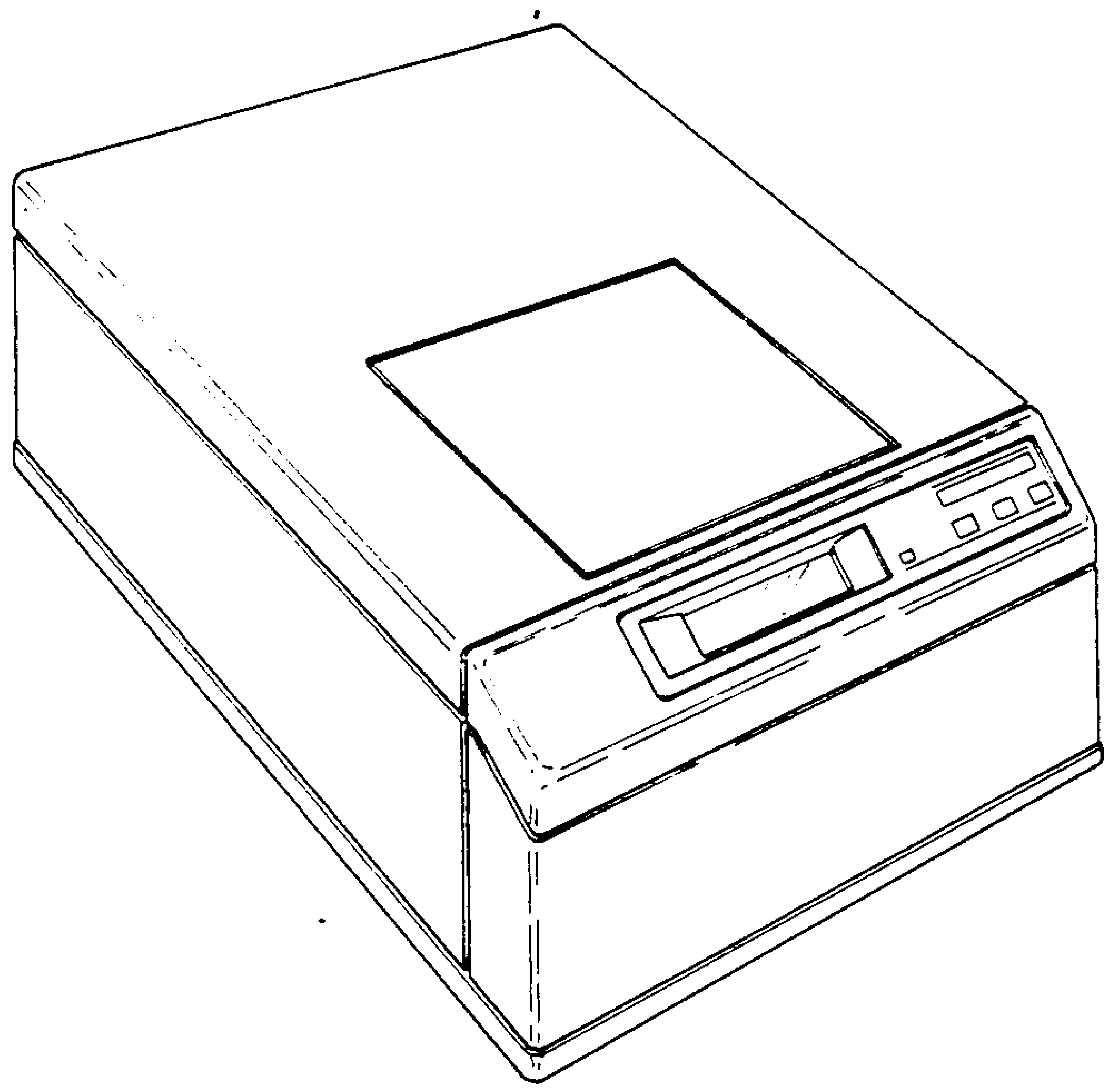
[57] **CLAIM**

The ornamental design for an automatic semiconductor wafer tester, as shown.

DESCRIPTION

FIG. 1 is a top and left front perspective view of an automatic semiconductor wafer tester showing my new design;
FIG. 2 is a top plan view thereof;
FIG. 3 is a front elevational view thereof;
FIG. 4 is a rear elevational view thereof;
FIG. 5 is a left side elevational view thereof;
FIG. 6 is a right side elevational view thereof.



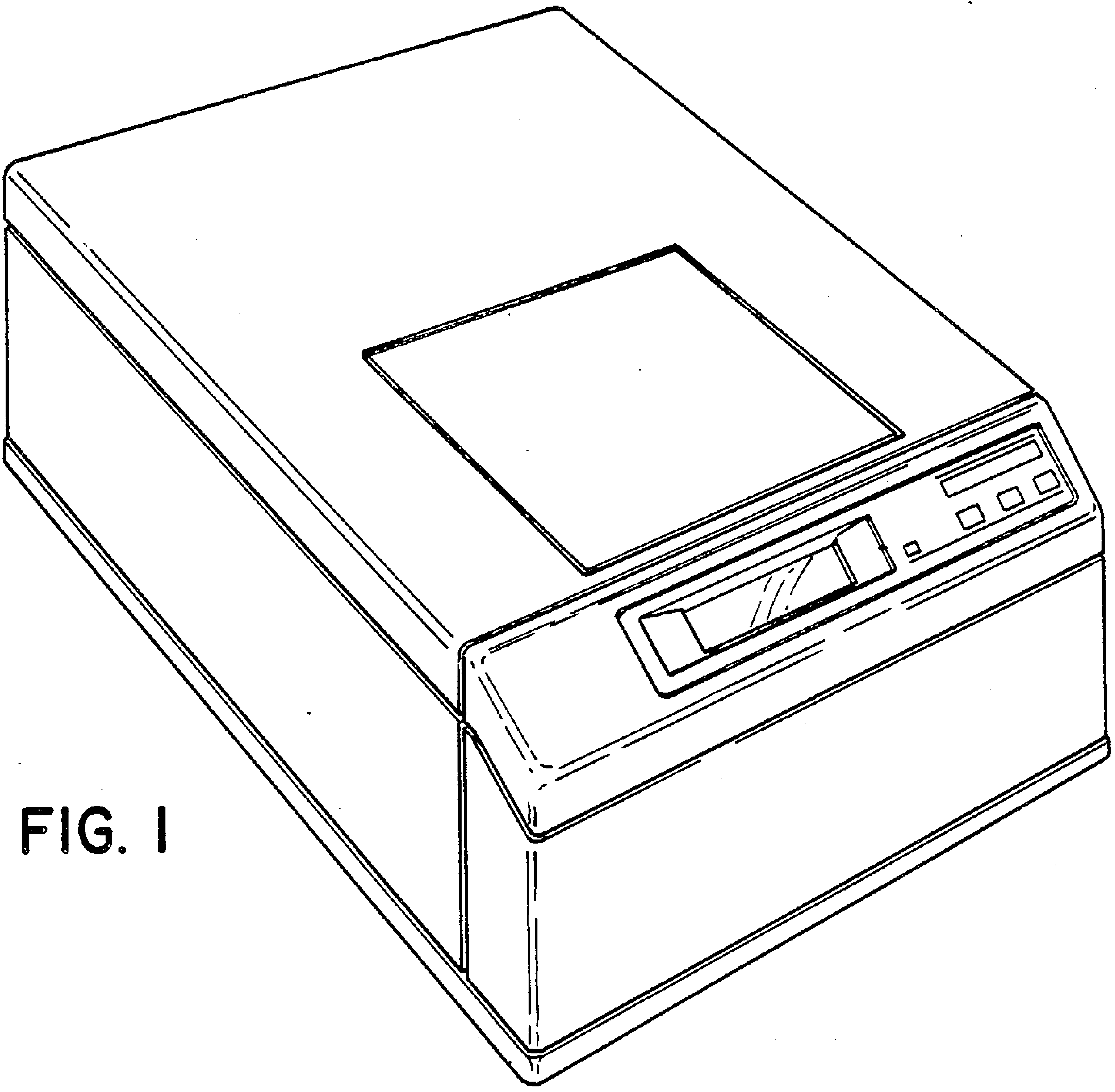


FIG. 1

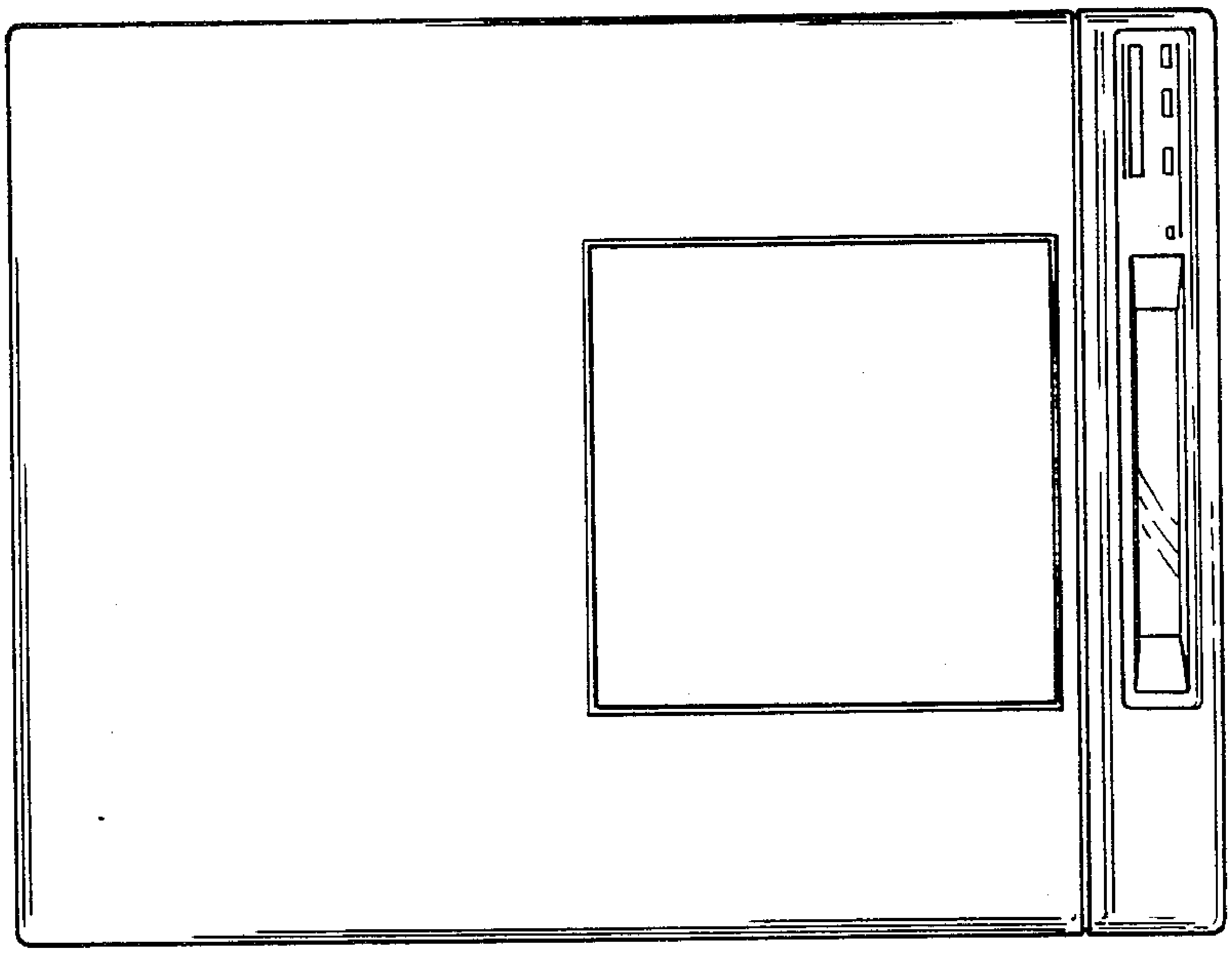


FIG. 2

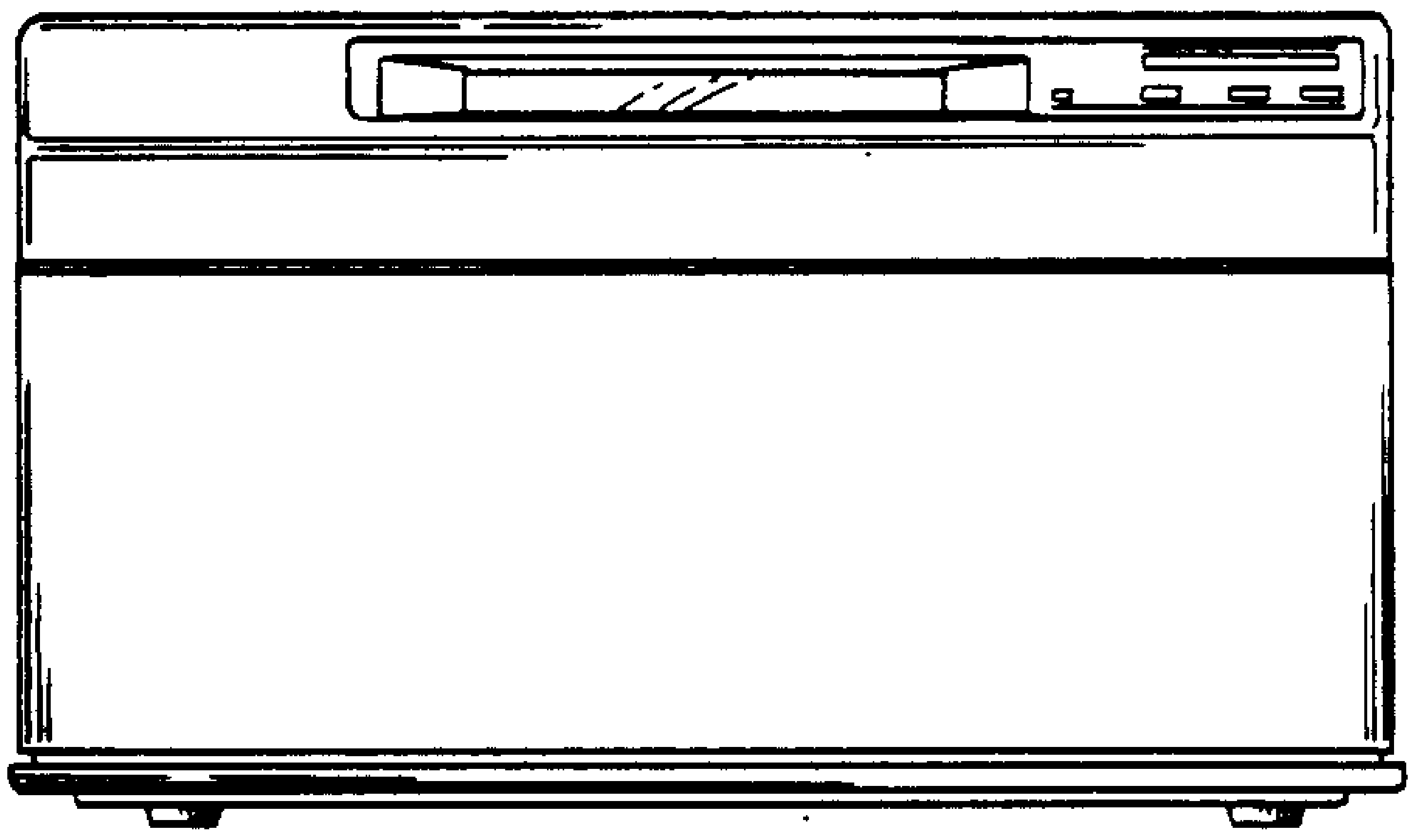


FIG. 3

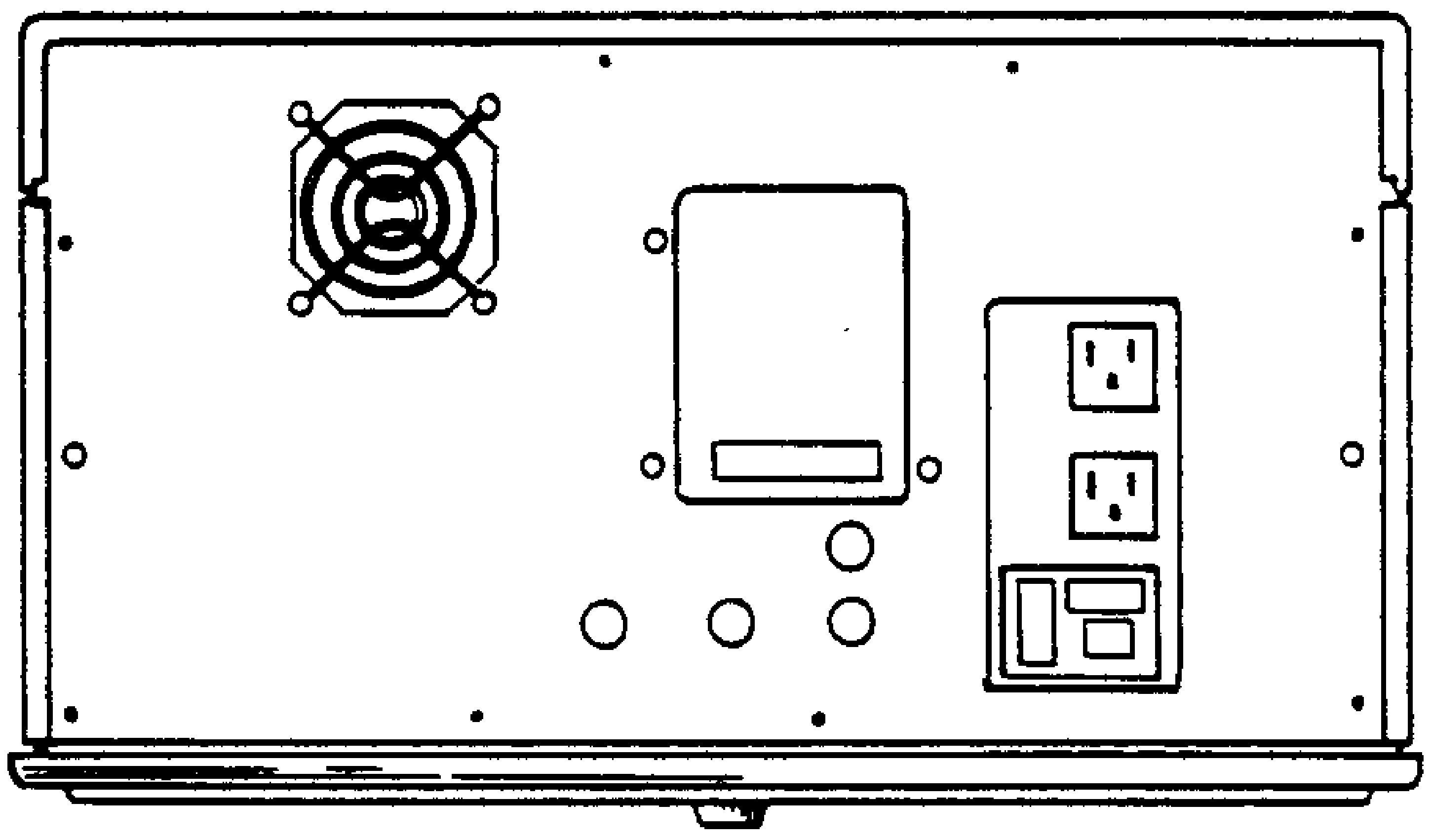


FIG. 4

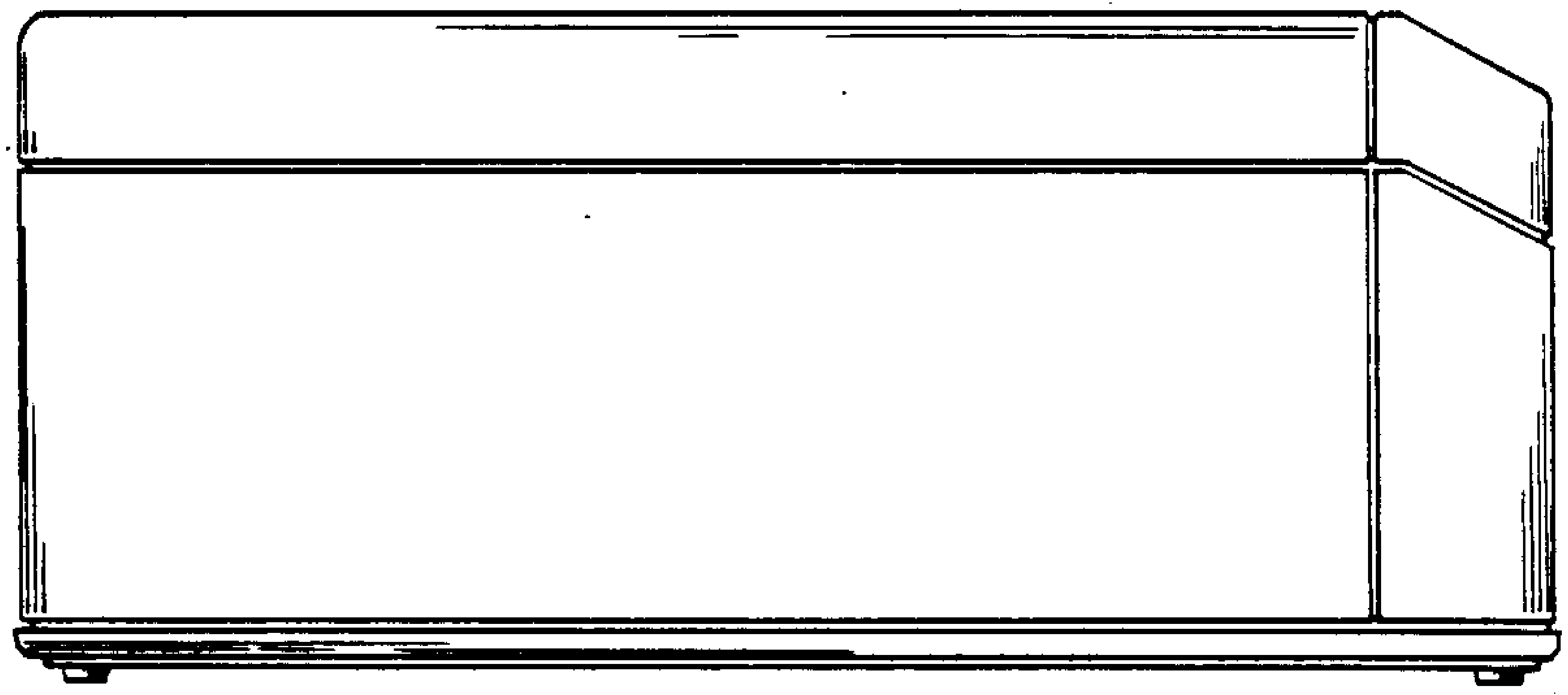


FIG. 5

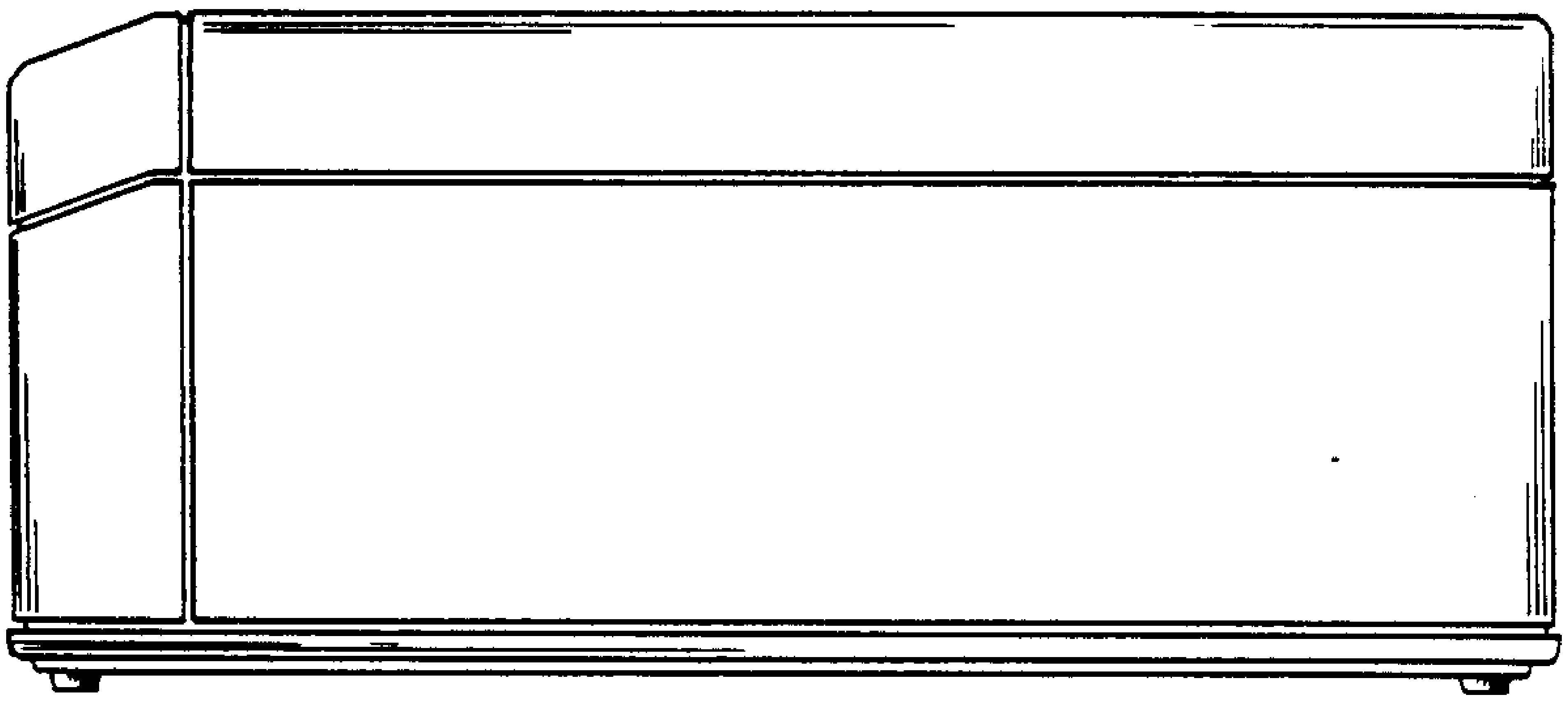


FIG. 6